Home | Login | Logout | Access Information | Alerts | Purchase History | Cart | Sitemap | Help

Welcome United States Patent and Trademark Office

Search Session History

BROWSE   SEARCH   IEEE XPLORE GUIDE   SUPPORT

Edit an existing query or compose a new query in the Search Query Display.

Select a search number (#) to:

- Add a query to the Search Query Display
- Combine search queries using AND, OR, or NOT
- Delete a search
- Run a search

Sun, 3 Aug 2008, 7:38:59 PM EST

Search Query Display

Recent Search Queries   Results

#1   (external test circuit<and>integrated circuit)<and>test mode   1

Help   Contact Us   Privacy & Security   IEEE.org

Indexed by
Inspec